

Muji Stop AF Commissioner for Patents 650. Box 1450 Alexandria, VA 22313-1450

Date 18 July 2007

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Reply Under 37 (FR 1.116 - Expedited Procedure Tech Center 2117

Appl. No.:

10/766,386

Applicants:

SWANSON, Travis et al.

Filed:

28 January 2004

Titled:

Generation of Memory Test Patterns for DLL Calibration

TC/A.U.:

2117

Examiner:

CHUNG, Phung M.

Docket No.:

PAT001098-000

AMENDMENT UNDER RULE 116

of to enter

Mail Stop AF Commissioner for Patents P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

In response to the Office action of 18 April 2007, please amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 3 of this paper.

Remarks/Arguments begin on page 7 of this paper.